

Design for accelerated testing of DC-link capacitors in photovoltaic inverters based on mission profiles

Sangwongwanich, Ariya; Shen, Yanfeng; **Chub, Andrii; Liivik, Elizaveta; Vinnikov, Dmitri**; Wang, Huai; Blaabjerg, Frede IEEE transactions on industry applications 2021 / p. 741–753 <https://doi.org/10.1109/TIA.2020.3030568> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Mission profile-based accelerated testing of DC-link capacitors in photovoltaic inverters

Sangwongwanich, Ariya; Shen, Yanfeng; **Chub, Andrii; Liivik, Elizaveta; Vinnikov, Dmitri**; Wang, Huai; Blaabjerg, Frede Thirty-Fourth Annual IEEE Applied Power Electronics Conference and Exposition, March 17 – 21, 2019, Anaheim, California 2019 / p. 2833-2840 : ill <https://doi.org/10.1109/APEC.2019.8721794> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Reliability analysis of battery energy storage system for various stationary applications

Bakeer, Abualkasim Ahmed Ali; Chub, Andrii; Shen, Yanfeng; Sangwongwanich, Ariya Journal of energy storage 2022 / art. 104217 <https://doi.org/10.1016/j.est.2022.104217> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Reliability evaluation of an impedance-source PV microconverter

Shen, Yanfeng; **Liivik, Elizaveta**; Blaabjerg, Frede; **Vinnikov, Dmitri**; Wang, Huai; **Chub, Andrii** 17th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral school of energy and geotechnology. III : Kuressaare, Estonia, January 15-20, 2018 2018 / p. 108-110 : ill http://ise.elnet.ee/record=b2950026~S2*est

Reliability evaluation of an impedance-source PV microconverter

Shen, Yanfeng; **Liivik, Elizaveta**; Blaabjerg, Frede; **Vinnikov, Dmitri**; Wang, Huai; **Chub, Andrii** 2018 IEEE Applied Power Electronics Conference and Exposition (APEC 2018), San Antonio, Texas, USA, 4-8 March 2018 2018 / p. 1104–1108 : ill <https://doi.org/10.1109/APEC.2018.8341154> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Reliability evaluation of isolated buck-boost DC-DC series resonant converter

Bakeer, Abualkasim Ahmed Ali; Chub, Andrii; Shen, Yanfeng IEEE open journal of power electronics 2022 / p. 131-141 <https://doi.org/10.1109/OJPEL.2022.3157200> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Reliability of DC-link capacitors in two-stage micro-inverters under different PV module sizes

Sangwongwanich, Ariya; Shen, Yanfeng; **Chub, Andrii; Liivik, Elizaveta; Vinnikov, Dmitri**; Wang, Huai; Blaabjerg, Frede ICPE 2019 - ECCE Asia : 10th International Conference on Power Electronics - ECCE Asia : "Green World with Power Electronics" : May 27-30, 2019 BEXCO, Busan, Korea 2019 / p. 1867-1872 : ill <https://ieeexplore.ieee.org/xpl/conhome/8786807/proceeding>

Reliability study of input side capacitors in impedance-source PV microconverters

Liivik, Elizaveta; Vinnikov, Dmitri; Chub, Andrii; Shen, Yanfeng IECON 2019 - 45th Annual Conference of the IEEE Industrial Electronics Society : proceedings 2019 / p. 5026–5032 : ill <https://doi.org/10.1109/IECON.2019.8927173> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Wear-out failure analysis of an impedance-source PV microinverter based on system-level electrothermal modeling

Shen, Yanfeng; **Chub, Andrii**; Wang, Huai; **Vinnikov, Dmitri; Liivik, Elizaveta**; Blaabjerg, Frede IEEE transactions on industrial electronics 2019 / p. 3914-3927 <https://doi.org/10.1109/TIE.2018.2831643> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Wear-out failure analysis of solar optiverter operating with 60- and 72-cell Si crystalline PV modules

Liivik, Liisa; Chub, Andrii; Sangwongwanich, Ariya; Shen, Yanfeng; **Vinnikov, Dmitri**; Blaabjerg, Frede IECON 2018 - 44th Annual Conference of the IEEE Industrial Electronics Society : proceedings 2018 / p. 6134-6140 : ill <https://doi.org/10.1109/IECON.2018.8592925>